Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10540658	MATHIES ET AL.
Examiner	Art Unit
Young J Kim	1637

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/8/2008	/YJK/		
see enclosed for text-search strategies	2/8/2008	/YJK/		
Updated - see enclosed for text-search strategies	10/2/2008	/YJK/		
Updated- see enclosed for text-search strategy	2/26/2009	/YJK/		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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